EAST SEARCH 6/10/2008

L#	Hits	Search String	Databases
L1	26	(((logic and gate and delay adj time) and rise and fall) and logical adj operation) an	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L2	5	(((logic and gate and delay adj time) and rise and fall) and logical adj operation) an	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L3	8	(((logic and gate and delay adj time) and rise and fall) and logical adj operation) an	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L4	46970	hasegawa.in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L5	956	hasegawa.in. and delay	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L6	121	(hasegawa.in. and delay) and NEC	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L7	45	(hasegawa.in. and delay) and NEC	USPAT
L1	12	((hasegawa.in. and delay) and NEC) and rise and fall	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L2	1628	delay adj calculat$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L3	26127	look adj3 table	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L4	74	(delay adj calculat$) and (look adj3 table)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L5	3	((delay adj calculat$) and (look adj3 table)) and library	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L6	473	(delay adj calculat$) and gate	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L7	67	((delay adj calculat$) and gate) and fall and rise	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L8	38	(((delay adj calculat$) and gate) and fall and rise) and simulat$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
L9	29	(((Blinne and delay time) and logic cell) and rise/fall) and estimating	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	7	optimizing adj signal adj timing	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	106402	logic adj circuit$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	310	(logic adj circuit$1) and (calculat$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	37	((logic adj circuit$1) and (calculat$3 adj delay)) and (logic$2 adj (information or op	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	112	(logic adj circuit$1) and (comput$5 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	96	(logic adj circuit$1) and (estimat$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	468	((logic adj circuit$1) and (calculat$3 adj delay)) or ((logic adj circuit$1) and (compu	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	56	(((logic adj circuit$1) and (calculat$3 adj delay)) or ((logic adj circuit$1) and (compu	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	7	(((logic adj circuit$1) and (calculat$3 adj delay)) and (logic$2 adj (information or op	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	5	(((((logic adj circuit$1) and (calculat$3 adj delay)) or ((logic adj circuit$1) and (comp	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	11	(((((logic adj circuit$1) and (calculat$3 adj delay)) or ((logic adj circuit$1) and (comp	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	33722	logic adj gate$1	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	179	(logic adj gate$1) and (calculat$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	47	(logic adj gate$1) and (comput$5 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	61	(logic adj gate$1) and (estimat$3 adj delay)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	268	((logic adj gate$1) and (calculat$3 adj delay)) or ((logic adj gate$1) and (comput$5	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
	38	(((logic adj gate$1) and (calculat$3 adj delay)) or ((logic adj gate$1) and (comput$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

0	((((logic adj gate$1) and (calculat$3 adj delay)) or ((logic adj gate$1) and (comput$	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
220	(logic adj circuit$1) and (delay with library)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
46	((logic adj circuit$1) and (delay with library)) and ("connection information" or "circu	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
0	((((logic adj circuit$1) and (delay with library)) and ("connection information" or "cir	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10	(((logic adj circuit$1) and (delay with library)) and ("connection information" or "circ	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
220	(logic adj circuit$1) and (delay with library)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
11	((logic adj circuit$1) and (delay with library)) and "logic information"	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB

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Results of search set L32:(logic adj gate$1) and ((calculat$3 adj delay) or (comput$5 adj delay) or (estimat$3 adj delay)) and (logic$2 adj (information or o

Document)ocument II	Title	Source	Issue Date	Current OR
US 20030006816 A1	Semiconductor integrated circuit device and microcomputer		20030109	327/158
US 20020113616 A1	Semiconductor integrated circuit		20020822	326/31
US 20020030521 A1	Semiconductor integrated circuit device and microcomputer		20020314	327/158
US 20020008560 A1	Variable delay circuit and semiconductor integrated circuit device		20020124	327/277
US 20010043103 A1	Semiconductor integrated circuit		20011122	327/175
US 20010043085 A1	Semiconductor integrated circuit		20011122	326/112
US 20010024136 A1	Semiconductor integrated circuit compensating variations of delay time		20010927	327/276
US 20010015658 A1	Semiconductor integrated circuit device capable of producing output thereof without being influenced by oth		20010823	326/104
US 6477695 B1	Methods for designing standard cell transistor structures		20021105	716/17
US 6477683 B1	Automated processor generation system for designing a configurable processor and method for the same		20021105	716/1
US 6476639 B2	Semiconductor integrated circuit device capable of producing output thereof without being influenced by oth		20021105	326/82
US 6472916 B2	Semiconductor integrated circuit device and microcomputer		20021029	327/158
US 6388483 B1	Semiconductor integrated circuit device and microcomputer		20020514	327/158
US 6380778 B2	Semiconductor integrated circuit		20020430	327/175
US 6304117 B1	Variable delay circuit and semiconductor integrated circuit device		20011016	327/158
US 6301692 B1	Method for designing layout of semiconductor integrated circuit, semiconductor integrated circuit obtained b		20011009	716/10
US 6295300 B1	Circuit and method for symmetric asynchronous interface		20010925	370/503
US 6215345 B1	Semiconductor device for setting delay time		20010410	327/279
US 6181184 B1	Variable delay circuit and semiconductor intergrated circuit device		20010130	327/278
US 6166577 A	Semiconductor integrated circuit device and microcomputer		20001226	327/278
US 6097884 A	Probe points and markers for critical paths and integrated circuits		20000801	716/4
US 5983008 A	Method for designing layout of semiconductor integrated circuit, semiconductor integrated circuit obtained b		19991109	716/6
US 5923569 A	Method for designing layout of semiconductor integrated circuit semiconductor integrated circuit obtained by		19990713	716/7
US 5764525 A	Method for improving the operation of a circuit through iterative substitutions and performance analyses of c		19980609	716/18

US 5661413 A	Processor utilizing a low voltage data circuit and a high voltage controller	19970826	326/80
US 5619418 A	Logic gate size optimization process for an integrated circuit whereby circuit speed is improved while circuit	19970408	716/6
US 5613062 A	Logic simulator	19970318	714/37
US 5606567 A	Delay testing of high-performance digital components by a slow-speed tester	19970225	714/732
US 5600583 A	Circuit and method for detecting if a sum of two multidigit numbers equals a third multidigit number prior to a	19970204	708/525
US 5508950 A	Circuit and method for detecting if a sum of two multibit numbers equals a third multibit constant number pri	19960416	708/525
US 5446748 A	Apparatus for performing logic simulation	19950829	714/814
US 5426591 A	Apparatus and method for improving the timing performance of a circuit	19950620	716/6
US 5270955 A	Method of detecting arithmetic or logical computation result	19931214	708/525
US 5124776 A	Bipolar integrated circuit having a unit block structure	19920623	257/204
US 5001751 A	Mode 4 reply decoder	19910319	342/45
US 4926478 A	Method and apparatus for continuously acknowledged link encrypting	19900515	705/75
US 4805216 A	Method and apparatus for continuously acknowledged link encrypting	19890214	380/283
US 3914580 A	TIMING CONTROL CIRCUIT FOR ELECTRONIC FUEL INJECTION SYSTEM	19751021	377/2

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